

<b>Notice of References Cited</b>	Application/Control No. 09/544,344	Applicant(s)/Patent Under Reexamination SNOW ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 1 of 5

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	Examiner Arlen Soderquist	Art Unit 1743	Page 2 of 5

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	Examiner Arlen Soderquist	Art Unit 1743	Page 3 of 5

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	B	US-			
	C	US-			
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Application/Control No.

09/544,344

Applicant(s)/Patent Under  
Reexamination  
SNOW ET AL.

Examiner

Arlen Soderquist

Art Unit

1743

Page 4 of 5

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	A	US-			
	B	US-			
	C	US-			
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	Examiner Arlen Soderquist	Art Unit 1743	Page 5 of 5

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